SCLS300A - JANUARY 1996 - REVISED MAY 1997

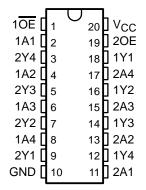
- 3-State Outputs Drive Bus Lines or Buffer Memory Address Registers
- High-Current Outputs Drive up to 15 LSTTL Loads
- Package Options Include Plastic Small-Outline (DW) and Ceramic Flat (W) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs

description

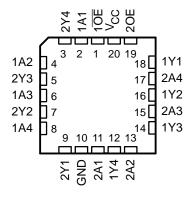
These octal buffers and line drivers are designed specifically to improve both the performance and density of 3-state memory address drivers, clock drivers, and bus-oriented receivers and transmitters. The 'HC241 are organized as two 4-bit buffers/drivers with separate output-enable (10E and 20E) inputs. When 10E is low or 20E is high, the device passes noninverted data from the A inputs to the Y outputs. When 10E is high or 20E is low, the outputs for the respective buffers/drivers are in the high-impedance state.

The SN54HC241 is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74HC241 is characterized for operation from –40°C to 85°C.

SN54HC241 . . . J OR W PACKAGE SN74HC241 . . . DW OR N PACKAGE (TOP VIEW)



SN54HC241 ... FK PACKAGE (TOP VIEW)



FUNCTION TABLES

INPU	JTS	ОИТРИТ
1OE	1A	1Y
L	Н	Н
L	L	L
Н	Χ	Z

INP	JTS	OUTPUT
20E	2A	2Y
Н	Н	Н
Н	L	L
L	Χ	Z



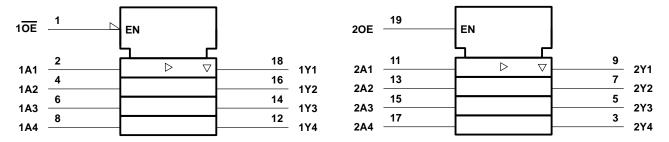
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SN54HC241, SN74HC241 OCTAL BUFFERS AND LINE DRIVERS WITH 3-STATE OUTPUTS

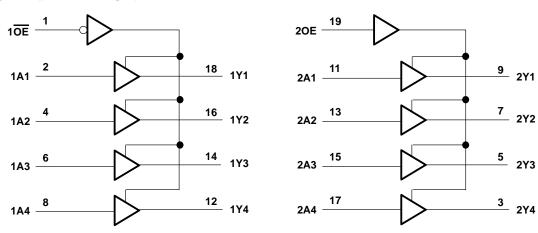
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logic symbol[†]



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range‡

Supply voltage range, V _{CC}	–0.5 V to 7 V
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$) (see Note 1)	±20 mA
Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CC}$) (see Note 1)	±20 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC})	±35 mA
Continuous current through V _{CC} or GND	±70 mA
Package thermal impedance, θ_{JA} (see Note 2): DW package	
N package	
Storage temperature range, T _{stg}	–65°C to 150°C

[‡] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.



^{2.} The package thermal impedance is calculated in accordance with JESD 51, except for through-hole packages, which use a trace length of zero.

recommended operating conditions

			SN	SN54HC241		SN74HC241			UNIT
			MIN	NOM	MAX	MIN	NOM	MAX	UNII
Vcc	Supply voltage		2	5	6	2	5	6	V
		V _{CC} = 2 V	1.5			1.5			
ViH	High-level input voltage	$V_{CC} = 4.5 \text{ V}$	3.15			3.15			V
		V _{CC} = 6 V	4.2			4.2			
		V _{CC} = 2 V	0		0.5	0		0.5	
VIL	Low-level input voltage	$V_{CC} = 4.5 \text{ V}$	0		1.35	0		1.35	V
		V _{CC} = 6 V	0		1.8	0		1.8	
٧ı	Input voltage		0		VCC	0		VCC	V
٧o	Output voltage		0		VCC	0		VCC	V
		V _{CC} = 2 V	0		1000	0		1000	
t _t	Input transition (rise and fall) time	$V_{CC} = 4.5 \text{ V}$	0		500	0		500	ns
		V _{CC} = 6 V	0		400	0		400	
TA	Operating free-air temperature		-55		125	-40		85	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADAMETED	TEST CONDITIONS		\ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \	Т	A = 25°C	;	SN54HC241		SN74HC241		
PARAMETER			vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
			2 V	1.9	1.998		1.9		1.9		
		I _{OH} = -20 μA	4.5 V	4.4	4.499		4.4		4.4		
Voн	VI = VIH or VIL		6 V	5.9	5.999		5.9		5.9		V
		$I_{OH} = -6 \text{ mA}$	4.5 V	3.98	4.3		3.7		3.84		
		$I_{OH} = -7.8 \text{ mA}$	6 V	5.48	5.8		5.2		5.34		
	VI = VIH or VIL	I _{OL} = 20 μA	2 V		0.002	0.1		0.1		0.1	
			4.5 V		0.001	0.1		0.1		0.1	
VOL			6 V		0.001	0.1		0.1		0.1	V
		I _{OL} = 6 mA	4.5 V		0.17	0.26		0.4		0.33	
		$I_{OL} = 7.8 \text{ mA}$	6 V		0.15	0.26		0.4		0.33	
lį	$V_I = V_{CC}$ or 0		6 V		±0.1	±100		±1000		±1000	nA
loz	$V_O = V_{CC}$ or 0		6 V		±0.01	±0.5		±10		±5	μΑ
Icc	$V_I = V_{CC}$ or 0,	I _O = 0	6 V			8		160		80	μΑ
C _i			2 V to 6 V		3	10		10		10	pF

SN54HC241, SN74HC241 OCTAL BUFFERS AND LINE DRIVERS WITH 3-STATE OUTPUTS

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switching characteristics over recommended operating free-air temperature range, C_L = 50 pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	Vaa	T,	√ = 25°C	;	SN54H	C241	SN74H	C241	UNIT		
PARAMETER	(INPUT)	(OUTPUT)	vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT		
			2 V		39	115		170		145			
^t pd	Α	Y	4.5 V		12	23		34		29	ns		
			6 V		11	20		29		25			
			2 V		60	150		225		190			
^t en	OE or OE	Y	Y	4.5 V		17	30		45		38	ns	
				6 V		15	26		38		32		
	OE or OE		2 V		40	150		225		190			
^t dis		or OE Y	Υ	4.5 V		18	30		45		38	ns	
			6 V		17	26		38		32			
			2 V		28	60		90		75			
t _t			Υ	Υ	4.5 V		8	12		18	·	15	ns
			6 V		6	10		15		13			

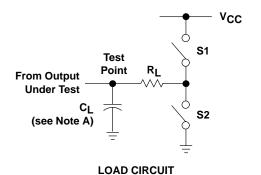
switching characteristics over recommended operating free-air temperature range, C_L = 150 pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	Vaa	T _A = 25°C			SN54HC241		SN74HC241		UNIT					
PARAMETER	(INPUT)	(OUTPUT)	VCC	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT					
			2 V		50	165		245		210						
^t pd	Α	Y	4.5 V		16	33		49		42	ns					
									6 V		14	28		42		35
	OE or OE			2 V		100	200		300		250					
t _{en}		Y	Y	4.5 V		20	40		60		50	ns				
					6 V		17	34		51		43				
				2 V		45	210		315		265					
t _t		Y	Υ	4.5 V		17	42		63		53	ns				
			6 V		13	36		53		45						

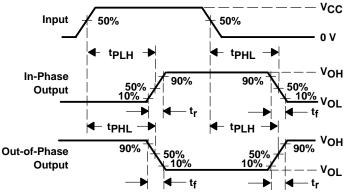
operating characteristics, $T_A = 25^{\circ}C$

	PARAMETER	TEST CONDITIONS	TYP	UNIT
C _{pd}	Power dissipation capacitance per buffer/driver	No load	35	pF

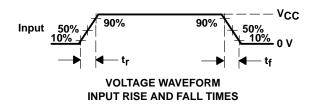
PARAMETER MEASUREMENT INFORMATION

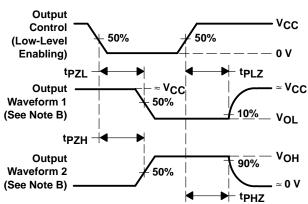


PARAI	METER	RL	CL	S1	S2	
	tPZH	1 k Ω	50 pF or	Open	Closed	
ten	tPZL	1 K22	150 pF	Closed	Open	
4	tPHZ	1 kΩ 50 pF		Open	Closed	
^t dis	tPLZ	1 K22	30 pr	Closed	Open	
t _{pd} or t _t		-	50 pF or 150 pF	Open	Open	



VOLTAGE WAVEFORMS
PROPAGATION DELAY AND OUTPUT TRANSITION TIMES





VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES FOR 3-STATE OUTPUTS

- NOTES: A. C_L includes probe and test-fixture capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, $Z_O = 50 \Omega$, $t_r = 6$ ns.
 - D. The outputs are measured one at a time with one input transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. tpzL and tpzH are the same as ten.
 - G. tplH and tpHL are the same as tpd.

Figure 1. Load Circuit and Voltage Waveforms



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